

Distinguished Seminar Series on Data Science & Artificial Intelligence

Data and AI Model Markets: From Sharing, Discovery, and Integration to Value and Ecosystems

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🕒 15:00 - 16:00 (HKT, UTC+8)

📍 Online via Zoom / PQ703

🗣️ English

✍️ Please register at <https://polyu.hk/YrkLX>
or scan the QR code



All are welcome!

Abstract

Sharing data and AI models has long been a bottleneck for the AI and data economies. In this talk, I will argue that the foundation for sharing lies in data and AI model discovery and integration. Despite the existence of data warehouses, data lakes, federated databases, and federated learning, many existing approaches are still far from solving the problem of sharing. To address this challenge, I will advocate for data and AI markets as a potential grand opportunity for data and AI model sharing at scale, especially for inter-organizational sharing. Drawing from our recent studies, I will demonstrate the exciting technical problems that arise in data and AI model markets. I will also offer my humble views on the future directions of data and AI model markets.

About the Speaker

Prof. Jian PEI is a Professor at Duke University, whose research focuses on data science, data mining, database systems, information retrieval, and applied machine learning. With his expertise in developing effective and efficient data analysis techniques for novel data-intensive applications and transferring them to products and business practice, he has been recognized as a Fellow of the Royal Society of Canada, the Canadian Academy of Engineering, ACM, and IEEE. His achievements include receiving several prestigious awards such as the 2017 ACM SIGKDD Innovation Award, the 2015 ACM SIGKDD Service Award, and the 2014 IEEE ICDM Research Contributions Award. He has previously served as the chair of ACM SIGKDD and as the Editor-in-Chief of IEEE TKDE.